

**Amendments to the Claims**

Claims 1-73 (canceled)

74.(original)A substrate including an anodized coating, said coating having a thickness quality of about 1.3 times better than a coating thickness quality of an anodized substrate made without a coating thickness monitor communicating with a controller, said coating thickness monitor including:

(a) at least one radiation source directed at at least a portion of the anodized substrate;

(b) at least one probe for capturing at least a portion of the radiation reflected and refracted by the anodized coating on the anodized substrate, the captured radiation being at least a portion of the radiation directed the anodized substrate from said radiation source; and

(c) at least one detector in communication with said at least one probe, said at least one detector capable of processing the captured radiation to allow a determination of at least the thickness of the anodized coating on the substrate

75.(original)The substrate of claim 74 further including an additional coating on said anodized coating

76.(original)A substrate including an anodized coating, said coating having a thickness quality of at least about 1.3 times better and a thickness consistency of about 1.6 time thereby having a quality x consistency product at least about 2 times better than a coating thickness quality x consistency product of an anodized substrate made without a coating thickness monitor communicating with a controller, said coating thickness monitor including:

(a) at least one radiation source directed at at least a portion of the anodized substrate;

(b) at least one probe for capturing at least a portion of the radiation reflected and refracted by the anodized coating on the anodized substrate, the captured radiation being at least a portion of the radiation directed the anodized substrate from said radiation source; and

(c) at least one detector in communication with said at least one probe, said at least one detector capable of processing the captured radiation to allow a determination of at least the thickness of the anodized coating on the substrate.

77.(original)A substrate including an anodized coating and an additional coating on said anodized coating, said anodized coating having a thickness quality of at least about 1.3 times better and a thickness consistency of about 1.6 time better thereby having a quality x consistency product at least about 2 time better than a coating thickness quality x consistency product of an anodized substrate made without a coating thickness monitor communicating with a controller, said coating thickness monitor including:

(a) at least one radiation source directed at at least a portion of the anodized substrate;

(b) at least one probe for capturing at least a portion of the radiation reflected and refracted by the anodized coating on the anodized substrate, the captured radiation being at least a portion of the radiation directed the anodized substrate from said radiation source; and

(c) at least one detector in communication with said at least one probe, said at least one detector capable of processing the captured radiation to allow a determination of at least the thickness of the anodized coating on the substrate.